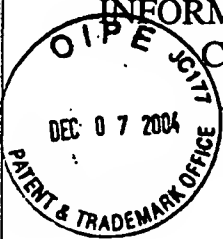
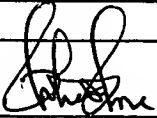


SHEET 1 OF 1

| INFORMATION DISCLOSURE CITATION IN AN APPLICATION (PTO-1449) | | | | ATTY. DOCKET NO. 005917 USA/FET/FET | | SERIAL NO. 09/998,372 | |
|---|---|----------|-----------------------|---|----------|---------------------------------|----|
| | | | | APPLICANT Young Joseph PAIK | | | |
| | | | | FILING DATE November 30, 2001 | | GROUP 3723 | |
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| EXAMINER'S INITIALS | PATENT NO. | DATE | NAME | CLASS | SUBCLASS | FILING DATE | |
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| EXAMINER'S INITIALS | PATENT NO. | DATE | COUNTRY | CLASS | SUBCLASS | Translation | |
| | | | | | | Yes | No |
| BB | WO 99/59200 | 11/18/99 | WIPO | | | X | |
| BB | WO 01/52319 | 07/19/01 | WIPO | | | X | |
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| BB | Williams, Randy, Dadi Gudmundsson, Kevin Monahan, Raman Nurani, Meryl Stoller and J. George Shanthikumar. October 1999. "Optimized Sample Planning for Wafer Defect Inspection," <i>Semiconductor Manufacturing Conference Proceedings, 1999 IEEE International Symposium on Santa Clara, CA</i> . Piscataway, NJ. pp. 43 - 46. | | | | | | |
| QQ | 23 July 2003. Invitation to Pay Additional Fees and Communication Relating to the Results of the Partial International Search for PCT/US02/19116. | | | | | | |
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| EXAMINER | | | | DATE CONSIDERED | | | |
| | | | | 02/23/05 | | | |

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

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|---|--|----------------------------------|
| <p align="center">INFORMATION DISCLOSURE CITATION IN AN APPLICATION (PTO-1449)</p>  | <p>ATTY. DOCKET NO. 005917 USA/FET/FET</p> | <p>SERIAL NO. 09/998,372</p> |
| | <p>APPLICANT Young Joseph PAIK</p> | |
| | <p>FILING DATE November 30, 2001</p> | <p>GROUP 3723</p> |
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DATE CONSIDERED

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| <p style="text-align: center;">INFORMATION DISCLOSURE CITATION IN AN APPLICATION (PTO-1449)</p> <p>PTO DEC 07 2004 PATENT & TRADEMARK OFFICE</p> | <p>ATTY. DOCKET NO. 005917 USA/FET/FET</p> | <p>SERIAL NO. 09/998,372</p> |
| | <p>APPLICANT Young Joseph PAIK</p> | |
| | <p>FILING DATE November 30, 2001</p> | <p>GROUP 3723</p> |
| <p>OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)</p> | | |
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| <p>EXAMINER</p> <p><i>[Signature]</i></p> | <p>DATE CONSIDERED</p> <p>02/23/05</p> | |

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